# MN3004

## 512-STAGE LOW NOISE BBD

#### ■ General Description

The MN3004 is a 512-stage high performance low noise BBD that provides a 85dB of signal to noise ratio (S/N) by increasing a capacity of capacitors with the same chip area, which is enabled by the improvement of silicon materials and process. There are many features for this device such as low insertion loss and no back gate bias voltage V<sub>BB</sub>, etc.

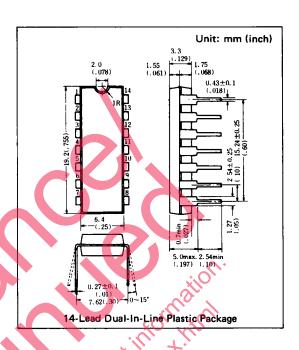
The MN3004 can delay analog signal of the audio band in the range of 2.56ms  $\sim$  25.6ms by adjusting a clock frequency.

#### Features

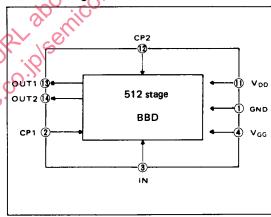
- Variable delay of audio signal: 2.56ms ~ 25.6ms
- Clock component cancellation capability.
- Low insertion loss:  $L_i = 1/5dB$  typ.
- Wide dynamic range:  $S/N \simeq 85dB$  typ.
- Wide frequency response:  $f_i \leq 0.3 \times f_{CD}$
- Clock frequency range: 10 ~ 100KHz
- Low noise:  $V_{no} = 0.21 \text{mVrms max}$ .
- Low distortion: THD = 0.4% typ.

### Applications

- Variable playback speed of tape recorder.
- Reverberation and echo effects of audio equipments such as
- Tremolo, vibrato and chorus effects in electronic musical instruments.
- Variable or fixed delay of analog signals.
- Please visit following Please Nttp://panasonic Telephone time compression and delay line for voice communication systems.
- Others



### ■ Block Diagram



#### Quick Reference Data

Item	Symbol	Value	Unit	
Supply Voltage	V <sub>DD</sub> , V <sub>GG</sub>	$-15, V_{DD}+1$	V	
Signal Delay Time	t <sub>D</sub>	2.56~25.6	ms	
Total Harmonic Distortion	THD	0.4	%	
Signal to Noise Ratio	S/N	85	dB	

### ■ Absolute Maximum Ratings (Ta = 25°C)

Item	Symbol	Ratings	Unit	
Terminal Voltage	V <sub>DD</sub> , V <sub>GG</sub> , V <sub>CP</sub> , V <sub>I</sub>	-18~+0.3	V	
Output Voltage	Vo	-18~+0.3	V	
Operating Temperature	Topr	-20~+60	°C	
Storage Temperature	Tstq	-55~+125	င	

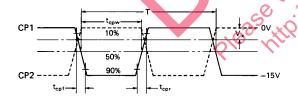
### Operating Conditions (Ta = 25°C)

ltem	Symbol	Condition	Min.	Тур.	Max.	Unit
Drain Supply Voltage	V <sub>DD</sub>		-14	-15	-16	٧
Gate Supply Voltage	V <sub>GG</sub>			$V_{DD}+1$		V
Clock Voltage "H" Level	V <sub>CPH</sub>		0		-1	V
Clock Voltage "L" Level	V <sub>CPL</sub>			V <sub>DD</sub>		
Clock Input Capacitance	C <sub>CP</sub>			A	350	pF
Clock Frequency	for		10		100	kHz
Clock Pulse Width *1	tcpw				0.5T*2	
Clock Rise Time *1	t <sub>cpr</sub>			1	500	ns
Clock Fall Time *1	t <sub>cpf</sub>				500	ns
Clock Cross Point	V <sub>x</sub>		0		103	٧
Input DC Bias	V <sub>Bias</sub>		<del> 5</del>	· C	-10	V

# ■ Electrical Characteristics (Ta = 25°C, $V_{DD} = V_{CPL} = -5V$ , $V_{CPH} = 0V$ , $V_{GG} = -14V$ , $R_L = KΩ$ )

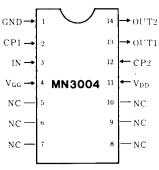
ltem	Symbol	Condition	Min	Typ.	Max.	Unit
Signal Delay Time	t <sub>D</sub>		2.56	W.	25.6	ms
Input Signal Frequency	fi	$f_{CP} = 40$ kHz, $V_1 \neq 1.8$ Vrms, 3dB down (0 dB at $f_1 = 1$ kHz)	120			kHz
Input Signal Swing	Vi	$f_{CP}$ =40kHz, $f_i = 1$ kHz, THD $\leq 2.5\%$	1.8			Vrms
Insertion Loss	Li	$f_{CP}=40kHz$ , $f_i=1kHz$ , $V_i=1.8Vrms$	<u>-4</u>	1.5	4	dB
Total Harmonic Distortion	THD	$f_{CP}=40$ kHz, $f_i=1$ kHz, $V_i=1$ Vrms		0.4	2.5	%
Noise Voltage	Vno	f <sub>CP</sub> = 100kHz Weighted by "A" curve			0.21	mVrms
Signal to Noise Ratio	S/N	allo anie		85		dB

### \*1 Clock Pulse Wavefroms



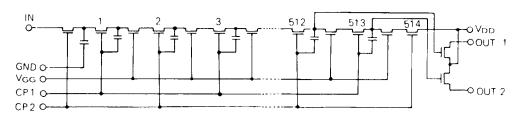
\*2 T = 1/fcp (Clock Period)

### Terminal Assignments

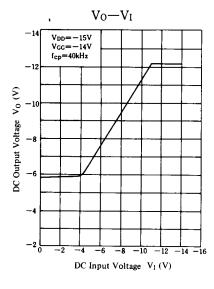


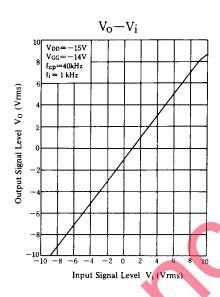
(Top View)

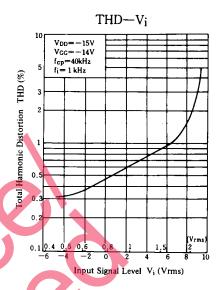
### ■ Circuit Diagram

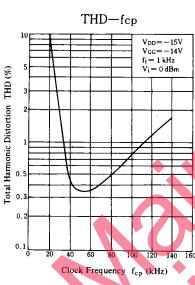


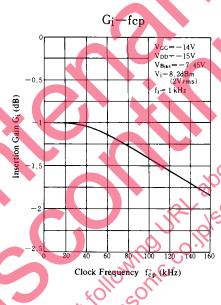
### **■** Typical Electrical Characteristic Curves

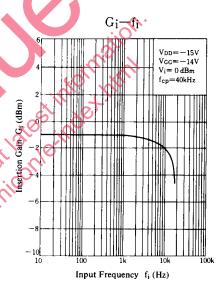


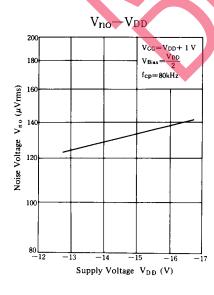


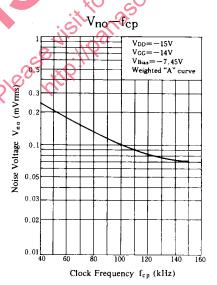




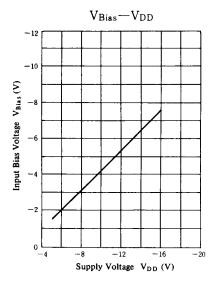


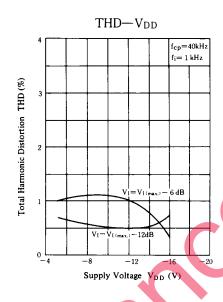


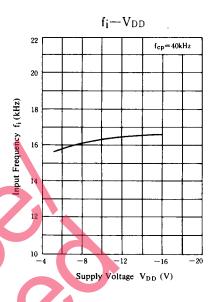


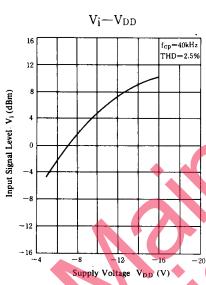


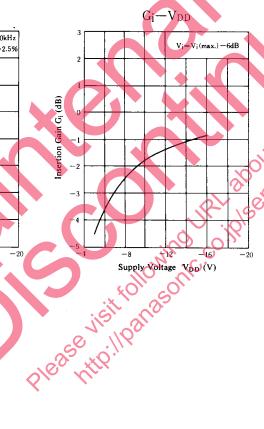
### ■ Supply Voltage Characteristics

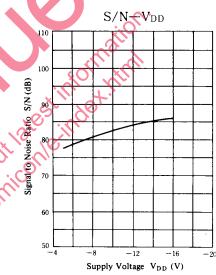




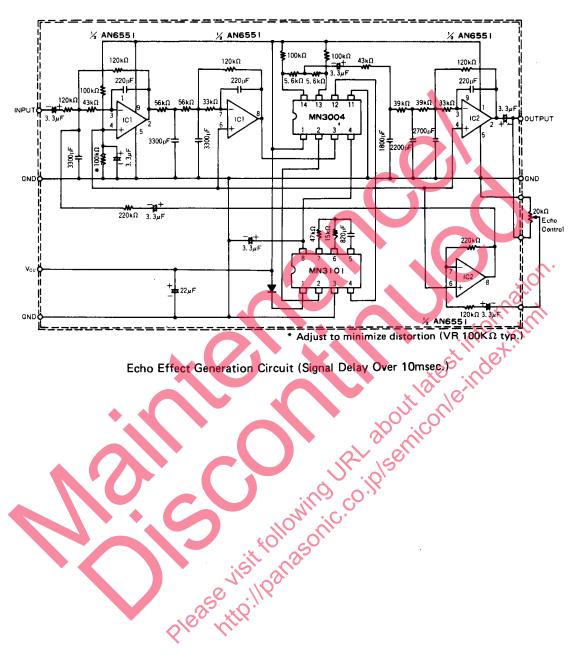








## ■ Application Circuit



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